

of **Riscure B.V.**  
**Security Lab**

This annex is valid from: **21-09-2023 to 01-09-2027**

Replaces annex dated: **17-11-2021**

**Location(s) where activities are performed under accreditation**

**Head Office**

Delftechpark 49  
 2628 XJ  
 Delft  
 The Netherlands

Location	Abbreviation/ location code
Delftechpark 49 2628 XJ Delft The Netherlands	DE
550 Kearny St. Suite 330 CA 94108 San Francisco United States of America	SF

No.	Material or product	Type of activity <sup>1</sup>	Internal reference number	Location
1	Embedded system security: <ul style="list-style-type: none"> <li>• smart card</li> <li>• mobile device</li> <li>• connected device</li> </ul>	Physical testing: <ul style="list-style-type: none"> <li>• Side Channel testing</li> <li>• Fault Injection testing</li> <li>• Physical modification</li> </ul>	CCDB-2013-05-002  Common Criteria/Application of Attack Potential to Smartcards, June 2020, Version 3.1	DE, SF
		Logical security testing: <ul style="list-style-type: none"> <li>• Software security testing</li> </ul>	CCDB-2013-05-002  Common Criteria/Application of Attack Potential to Smartcards, June 2020, Version 3.1	

This annex has been approved by the Board of the Dutch Accreditation Council, on its behalf,

J.A.W.M. de Haas

<sup>1</sup> If there is a referral to a code starting with NAW, NAP, EA or IAF, this concerns a scheme mentioned on the [RvA-BR010-lijst](#).  
 If no date or version number is mentioned for a normative document, the accreditation concerns the most current version of the document or scheme.

Annex to declaration of accreditation (scope of accreditation)

Normative document: EN ISO/IEC 17025:2017

Registration number: **L 605**

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No.	Material or product	Type of activity <sup>1</sup>	Internal reference number	Location
2	IT products and systems	Evaluation of IT-security products	- Common Criteria v3.1 - NEN-ISO/IEC 15408-1, -2, -3 - Common Evaluation Methodology v3.1 -NEN-ISO/IEC 18045  For EAL1-EAL7, ALC_FLR.3, ASE TSS.2	DE